09/922,479

L Number	Hits	Search Text	DB	Time stamp
1	3	(("5644578") or ("5568437") or ("5659551")).PN.	USPAT	2004/06/26 16:56
2	54	"5568437"	USPAT	2004/06/26 16:58
3	1043897	integrated circuit with built-in self-test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 16:58
4	8291826	external testing device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 16:59
5	699359	(integrated circuit with built-in self-test) and (external testing device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:01
6	469523	evaluat$3 and (test result$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:02
7	5596704	reading out result$1 and (external testing device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:05
8	412642	(evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:07
9	86855	((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:10
10	4891759	test result memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:10
11	86855	(((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:12
12	10276977	self-test control device	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:13
13	85250	((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:18
14	4889	714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:20

15	582	(((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:22
16	848447	error$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:22
17	303	((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)) and error$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:23
18	3340	"BIST" or "built-in self-test"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:23
19	88	(((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)) and error$1) and ("BIST" or "built-in self-test")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:24
20	1257816	built-in self-test controller$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:24
21	86	((((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)) and error$1) and ("BIST" or "built-in self-test")) and (built-in self-test controller$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:24
22	3497997	component$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:26
23	54	(((((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)) and error$1) and ("BIST" or "built-in self-test")) and (built-in self-test controller$1)) and component$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:26
24	354364	wafer$!	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:27
25	20	(((((((((((integrated circuit with built-in self-test) and (external testing device)) and ((evaluat$3 and (test result$1)) and (reading out result$1 and (external testing device)))) and (test result memory)) and (self-test control device)) and (714/733.ccls. or 714/734.ccls. or 714/724.ccls. or 714/30.ccls. or 714/726.ccls.)) and error$1) and ("BIST" or "built-in self-test")) and (built-in self-test controller$1)) and component$1) and wafer$!	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/26 17:28